| ΓΔ | IN | Æ | C | , |
|---------|----|---|----|---|
| \perp | ш | 4 | ٠, | |

- 1. A deposition system for oblique deposition comprising:
 - a source of vaporized species;
 - a substrate contacted by vaporized species forming a tilted thin film; and
 - a collimator having an array of holes oriented at approximately an oblique angle θ , the collimator placed between the source and the substrate to limit the passage to vaporized species traveling at approximately an oblique angle θ .

10

5

- 2. The deposition system of claim 1 wherein the oblique angle θ is greater than 35° and less than 90°.
- 3. The deposition system of claim 1 wherein the oblique angle θ is greater than 55° and less than 75°.
 - 4. The deposition system of claim 1 wherein the holes are arranged in a radial pattern.
- 20 5. The deposition system of claim 1 wherein the holes are arranged so that the vaporized species passing through the collimator subsequently contact the substrate to form a radial pattern in the tilted thin film.
 - 6. The deposition system of claim 1 wherein the holes are arranged in a circumferential pattern.
 - 7. The deposition system of claim 1 wherein the holes are arranged so that the vaporized species passing through the collimator subsequently contact the substrate to form a circumferential pattern in the tilted thin film.

- 8. The deposition system of claim 1 wherein the holes are arranged so that the vaporized species passing through the collimator subsequently contact the substrate to form a tilted thin film with azimuthal symmetry.
- 5 9. A method for collimated oblique deposition onto a substrate, the method comprising:

placing a collimator between a source of a material and the substrate, wherein the collimator has a surface, and the collimator has openings tilted at an angle relative to a surface normal;

surrace normal;

applying energy such that vaporized species leave the source and travel through the openings; and

depositing the vaporized species on the substrate resulting in a tilted thin film.

15

10

- 10. The method of claim 9 additionally comprising:
 - applying differential pumping such that a first chamber is subjected to a first pressure and a second chamber is subjected to a second pressure where the first pressure is less than the second pressure.

20

- 11. The method of claim 9 wherein the angle is greater than approximately 55° and less than approximately 75°.
- 25 12. The method of claim 9 wherein the openings are arranged in a radial pattern.
 - 13. The method of claim 9 wherein the vaporized species are deposited on the substrate in a radial pattern.

| | 14. | The method of claim 9 wherein the openings are arranged in a | | | |
|----|--------------------------|--|--|--|--|
| | circumferential pattern. | | | | |
| | | The state of the s | | | |
| 5 | 15. | The method of claim 9 wherein the vaporized species are | | | |
| | deposited on | the substrate in a circumferential pattern. | | | |
| | 16. | A method of forming a magnetic storage media on a substrate, | | | |
| | the magnetic | storage media comprising at least one thin film tilted at an angle | | | |
| 10 | relative to a | surface normal and having azimuthal symmetry, the method | | | |
| | comprising: | | | | |
| | | depositing one or more materials through a collimator onto a | | | |
| | | substrate, wherein the collimator has openings tilted at an | | | |
| | | angle greater than 45° and less than 90° relative to a | | | |
| 15 | | surface normal; and | | | |
| | | rotating the substrate during deposition. | | | |
| | 17. | The method of claim 16, wherein the materials are from a source, | | | |
| | the method a | dditionally comprising: | | | |
| 20 | | applying a first vacuum between the collimator and substrate; | | | |
| | | applying a second vacuum between the collimator and the source; | | | |
| | | and | | | |
| | | applying differential pumping such that the substrate is subjected | | | |
| | | to a first pressure and the source is subjected to a second | | | |
| 25 | | pressure where the first pressure is less than the second | | | |
| | | pressure. | | | |

- 18. The method of claim 16 wherein the openings are distributed across the collimator for deposition of the materials at a substantially uniform thickness.
- 5 19. A collimator for oblique deposition of a deposition beam resulting in a tilted thin film with azimuthal symmetry, the collimator comprising:
 - a block for intercepting a portion of the deposition beam, the block having a surface and a center; and
- a plurality of openings in the block for passage of a portion of the deposition beam, the openings being tilted at an angle relative to an axis drawn normal to the block.
- 20. The collimator of claim 1 wherein the angle is greater than 35° and less than 90°.
 - 21. The collimator of claim 19 wherein the angle is greater than 55° and less than 75°.
- 20 22. The collimator of claim 19 wherein the openings are arranged in a radial pattern.
 - 23. The collimator of claim 19 wherein the opening are arranged in a circumferential pattern.

25